



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Gordhan Barevadia et al.

Serial No: 10/667,879

Filed: 09/22/2003

Customer No.: 23494

Docket No.: TI-36281

Art Unit: 2138

Examiner: Phung M. Chung

Conf. No.: 1157

Title: Mechanism to Enhance Observability of Integrated Circuit Failures During Burn-In Tests

TRANSMITTAL OF FORMAL DRAWINGS

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Attn: Official Draftsperson

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)
I hereby certify that the above correspondence is being deposited
with the U.S. Postal Service as First Class Mail in an envelope
addressed to: Commissioner of Patents, P. O. Box 1450,
Alexandria, VA 22313-1450.


3-20-06
Date Marianna Smith
Marianna Smith

Dear Sir:

Enclosed is one (1) sheet of formal drawings. These drawings are being submitted to replace drawings previously submitted on 9/22/2003.

Charge any necessary fee to Deposit Account No. 20-0668. The original and a copy of this authorization are enclosed.

Respectfully submitted,


Abdul Zindani
Attorney for Applicants
Reg. No. 46,091

Texas Instruments Incorporated
P.O. Box 655474, MS 3999
Dallas, TX 75265
(972) 917-5137